

# **QUADRUPLE RS-485 DIFFERENTIAL LINE DRIVERS**

Check for Samples: SN65LBC174A SN75LBC174A

#### **FEATURES**

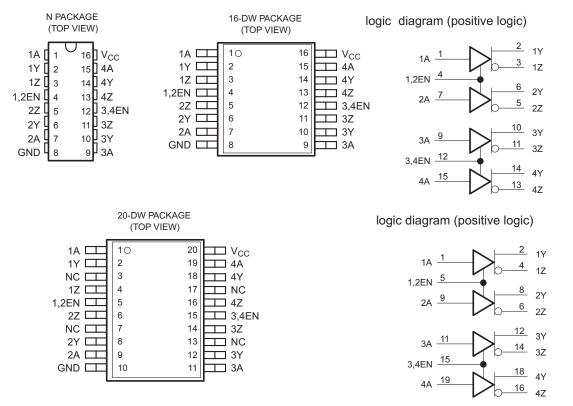
- Designed for TIA/EIA-485, TIA/EIA-422 and ISO 8482 Applications
- Signaling Rates (1) up to 30 Mbps
- Propagation Delay Times < 11 ns</li>
- Low Standby Power Consumption 1.5-mA Max
- (1) The signaling rate of a line is the number of voltage transitions that are made per second expressed in the units bps (bits per second).

- Output ESD Protection: 12 kV
- Driver Positive- and Negative-Current Limiting
- Power-Up and Power-Down Glitch-Free for Line Insertion Applications
- Thermal Shutdown Protection
- Industry Standard Pin-Out, Compatible With SN75174, MC3487, DS96174, LTC487, and MAX3042

#### **DESCRIPTION**

The SN65LBC174A and SN75LBC174A are quadruple differential line drivers with 3-state outputs, designed for TIA/EIA-485 (RS-485), TIA/EIA-422 (RS-422), and ISO 8482 applications.

These devices are optimized for balanced multipoint bus transmission at signaling rates up to 30 million bits per second. The transmission media may be printed-circuit board traces, backplanes, or cables. The ultimate rate and distance of data transfer is dependent upon the attenuation characteristics of the media and the noise coupling to the environment.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### **DESCRIPTION (CONTINUED)**

Each driver features current limiting and thermal-shutdown circuitry making it suitable for high-speed multipoint applications in noisy environments. These devices are designed using LinBiCMOS<sup>®</sup>, facilitating low power consumption and robustness.

The two EN inputs provide pair-wise driver enabling, or can be externally tied together to provide enable control of all four drivers with one signal. When disabled or powered off, the driver outputs present a high-impedance to the bus for reduced system loading.

The SN75LBC174A is characterized for operation over the temperature range of 0°C to 70°C. The SN65LBC174A is characterized for operation over the temperature range of –40°C to 85°C.

**Table 1. AVAILABLE OPTIONS** 

		PACKAGE		
T <sub>A</sub>	16-PIN PLASTIC SMALL OUTLINE <sup>(1)</sup> (JEDEC MS-013)	20-PIN PLASTIC SMALL OUTLINE <sup>(1)</sup> (JEDEC MS-013)	16-PIN PLASTIC THROUGH-HOLE (JEDEC MS-001)	
000 to 7000	SN75LBC174A16DW	SN75LBC174ADW	SN75LBC174AN	
0°C to 70°C		MARKED AS 75LBC174A		
400C to 050C	SN65LBC174A16DW	SN65LBC174DW	SN65LBC174AN	
–40°C to 85°C	·	MARKED AS 65LBC174A		

<sup>(1)</sup> Add R suffix for taped and reeled version.

Table 2. FUNCTION TABLE (EACH DRIVER)(1)

INPUT	ENABLE	OUTPUT	OUTPUT							
Α	EN	Y	Z							
L	Н	L	Н							
Н	Н	Н	L							
OPEN	Н	Н	L							
L	OPEN	L	Н							
Н	OPEN	Н	L							
OPEN	OPEN	Н	L							
X	L	Z	Z							

(1) H = high level, L = low level, X = irrelevant, Z = high impedance (off)



#### **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range (unless otherwise noted)(1)

			VALUE / UNIT		
Supply voltage rar	nge, V <sub>CC</sub> <sup>(2)</sup>	–0.3 V to 6 V			
Voltage range at a	any bus (DC)		–10 V to 15 V		
Voltage range at a	any bus (transient pulse through 100 C	2, see Figure 8)	−30 V to 30 V		
Input voltage rang	e at any A or EN terminal, V <sub>I</sub>		-0.5 V to V <sub>CC</sub> + 0.5 V		
	Human body model (3)	Y, Z, and GND	±12 kV		
Electrostatic discharge	Human body model (**)	All pins	±5 kV		
distriarge	Charged-device model (4)	All pins	±1 kV		
Storage temperatu	ure range, T <sub>stg</sub>		−65°C to 150°C		
Continuous power	dissipation	See Dissipation Rating Table			

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- 2) All voltage values, except differential I/O bus voltages, are with respect to GND.
- 3) Tested in accordance with JEDEC standard 22, Test Method A114-A.
- (4) Tested in accordance with JEDEC standard 22, Test Method C101.

#### **Table 3. DISSIPATION RATING TABLE**

PACKAGE (1)	JEDEC BOARD MODEL	T <sub>A</sub> ≤ 25°C POWER RATING	DERATING FACTOR (2) ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING
16 DW	LOW K	1200 mW	9.6 mW/°C	769 mW	625 mW
IO DVV	HIGH K	2240 mW	17.9 mW/°C	1434 mW	1165 mW
20 DW	LOW K	1483 mW	11.86 mW/°C	949 mW	771 mW
20 DVV	HIGH K	2753 mW	22 mW/°C	1762 mW	1432 mW
16 N	LOW K	1150 mW	9.2 mW/°C	736 mW	598 mW

<sup>(1)</sup> For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

#### RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>		4.75	5	5.25	V
Voltage at any bus terminal	Y, Z	<b>-</b> 7		12	V
High-level input voltage, V <sub>IH</sub>	A EN	2		V <sub>CC</sub>	V
Low-level input voltage, V <sub>IL</sub>	A, EN	0		0.8	V
Output current		-60		60	mA
Operating free-air	SN75LBC174A	0		70	°C
temperature, T <sub>A</sub>	SN65LBC174A	-40		85	

<sup>(2)</sup> This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.



#### **ELECTRICAL CHARACTERISTICS**

over recommended operating conditions

	PARAMETER	TEST COND	MIN	TYP (1)	MAX	UNIT	
V <sub>IK</sub>	Input clamp voltage	I <sub>I</sub> = -18 mA	-1.5	-0.77		V	
Vo	Open-circuit output voltage	Y or Z, No load		0		$V_{CC}$	V
		No load (open circuit)		3		$V_{CC}$	
$ V_{OD(SS)} $	Steady-state differential output voltage magnitude (2)	$R_L = 54 \Omega$ , See Figure 1		1	1.6	2.5	V
	maginidae	With common-mode loading	g, See Figure 2	1	1.6	2.5	
$\Delta V_{OD(SS)}$	Change in steady-state differential output voltage between logic states	See Figure 1		-0.1		0.1	V
V <sub>OC(SS)</sub>	Steady-state common-mode output voltage	See Figure 3	2	2.4	2.8	V	
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage between logic states	See Figure 3	-0.02		0.02	V	
I <sub>I</sub>	Input current	A, EN	-50		50	μΑ	
	Short aircuit output ourrant		V <sub>I</sub> = 0 V	-200		200	mA
I <sub>OS</sub>	Short-circuit output current	V <sub>TEST</sub> = -7 V to 12 V, See	$V_I = V_{CC}$	-200		200	IIIA
l <sub>OZ</sub>	High-impedance-state output current	Figure 7	EN at 0 V	-50		50	
I <sub>O(OFF)</sub>	Output current with power off		$V_{CC} = 0 V$	-10		10	μA
	Cumply ourrent	V 0 V or V No load	All drivers enabled			23	A
I <sub>CC</sub>	Supply current	$V_I = 0 \text{ V or } V_{CC}$ , No load			1.5	mA	
<u></u>	Innut Canacitanas	A inputs		13		pF	
C <sub>IN</sub> Input Capacitance		EN inputs		21		pF	

<sup>(1)</sup> All typical values are at  $V_{CC} = 5 \text{ V}$  and 25°C.

#### **SWITCHING CHARACTERISTICS**

over recommended operating conditions

PARAI	METER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	Propagation delay time, low-to-high level output		5.5	8	11	ns
t <sub>PHL</sub>	Propagation delay time, high-to-low level output		5.5	8	11	ns
t <sub>r</sub>	Differential output voltage rise time		3	7.5	11	ns
t <sub>f</sub>	Differential output voltage fall time	$R_1 = 54 \Omega, C_1 = 50 pF,$	3	7.5	11	ns
	Dulas akaw it to I	See Figure 4		0.6	2	
t <sub>sk(p)</sub>	Pulse skew  t <sub>PLH</sub> - t <sub>PHL</sub>			0.6	2	ns
t <sub>sk(o)</sub>	Output skew <sup>(1)</sup>				2	ns
t <sub>sk(pp)</sub>	Part-to-part skew <sup>(2)</sup>				3	ns
t <sub>PZH</sub>	Propagation delay time, high-impedance-to-high-level output	See Figure 5			25	ns
t <sub>PHZ</sub>	Propagation delay time, high-level-output-to-high impedance	See Figure 5			25	ns
t <sub>PZL</sub>	Propagation delay time, high-impedance-to-low-level output	See Figure 6			30	ns
t <sub>PLZ</sub>	Propagation delay time, low-level-output-to-high impedance	See Figure 6			20	ns

<sup>(1)</sup> Output skew (t<sub>sk(o)</sub>) is the magnitude of the time delay difference between the outputs of a single device with all of the inputs connected together.

<sup>(2)</sup> The minimum V<sub>OD</sub> may not fully comply with TIA/EIA-485-A at operating temperatures below 0°C. System designers should take the possibly lower output signal into account in determining the maximum signal transmission distance.

<sup>(2)</sup> Part-to-part skew (t<sub>sk(pp)</sub>) is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same input signals, the same supply voltages, at the same temperature, and have identical packages and test circuits.



#### PARAMETER MEASUREMENT INFORMATION

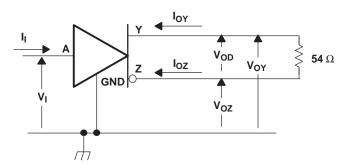


Figure 1. Test Circuit, V<sub>OD</sub> Without Common-Mode Loading

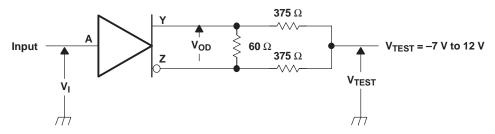
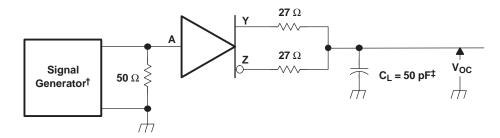


Figure 2. Test Circuit, V<sub>OD</sub> With Common-Mode Loading

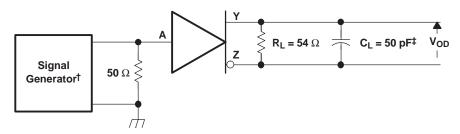


 $<sup>^{\</sup>dagger}$  PRR = 1 MHz, 50% Duty Cycle,  $t_{r}$  < 6 ns,  $t_{f}$  < 6 ns,  $Z_{O}$  = 50  $\Omega$ 

Figure 3. V<sub>OC</sub> Test Circuit

<sup>&</sup>lt;sup>‡</sup> Includes probe and jig capacitance





- $^{\dagger}$  PRR = 1 MHz, 50% Duty Cycle,  $t_{r}$  < 6 ns,  $t_{f}$  < 6 ns,  $Z_{O}$  = 50  $\Omega$
- <sup>‡</sup> Includes probe and jig capacitance

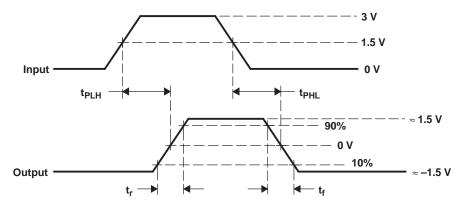
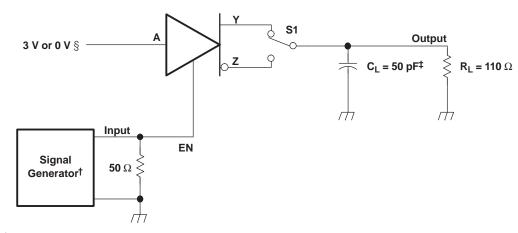


Figure 4. Output Switching Test Circuit and Waveforms





- <sup>†</sup> PRR = 1 MHz, 50% Duty Cycle,  $t_r$  < 6 ns,  $t_f$  < 6 ns,  $Z_O$  = 50  $\Omega$
- <sup>‡</sup> Includes probe and jig capacitance
- § 3 V if testing Y output, 0 V if testing Z output

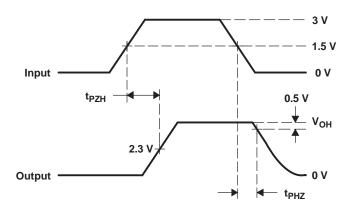
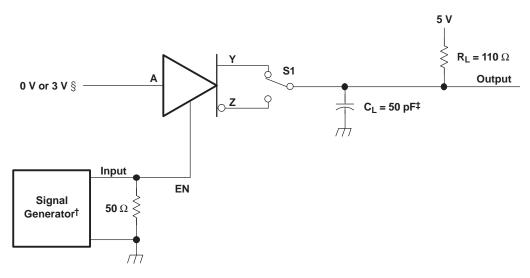


Figure 5. Enable Timing Test Circuit and Waveforms,  $t_{\text{PZH}}$  and  $t_{\text{PHZ}}$ 





- $^{\dagger}$  PRR = 1 MHz, 50% Duty Cycle,  $\rm t_f$  < 6 ns,  $\rm t_f$  < 6 ns,  $\rm Z_O$  = 50  $\rm \Omega$
- <sup>‡</sup> Includes probe and jig capacitance
- § 3 V if testing Y output, 0 V if testing Z output

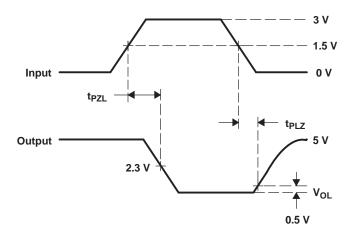


Figure 6. Enable Timing Test Circuit and Waveforms,  $t_{\text{PZL}}$  and  $t_{\text{PLZ}}$ 



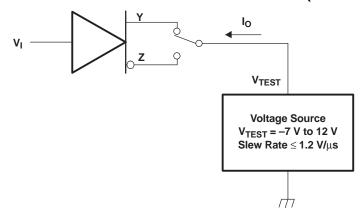


Figure 7. Test Circuit, Short-Circuit Output Current

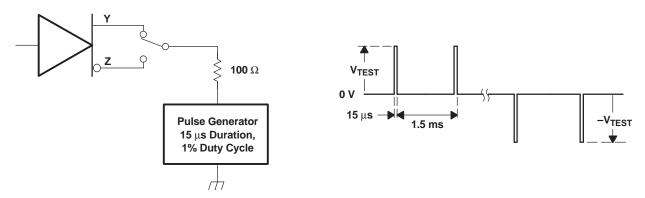
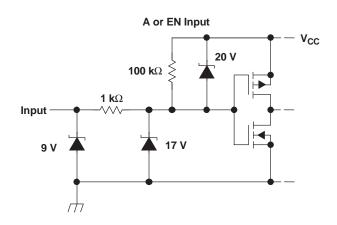
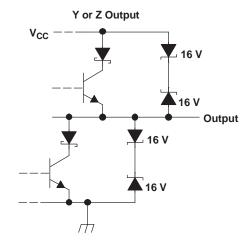


Figure 8. Test Circuit Waveform, Transient Overvoltage Test

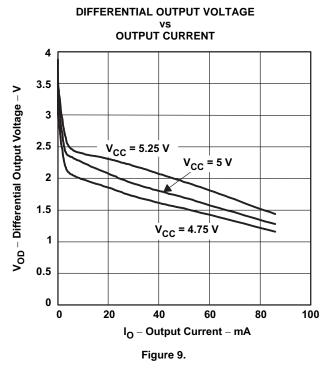
#### **EQUIVALENT INPUT AND OUTPUT SCHEMATIC DIAGRAMS**

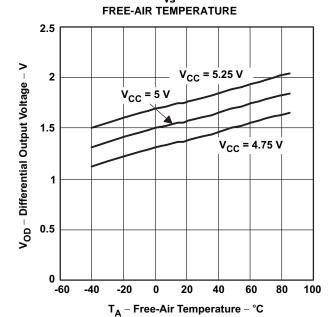






#### TYPICAL CHARACTERISTICS





**DIFFERENTIAL OUTPUT VOLTAGE** 

# PROPAGATION DELAY TIME vs FREE-AIR TEMPERATURE

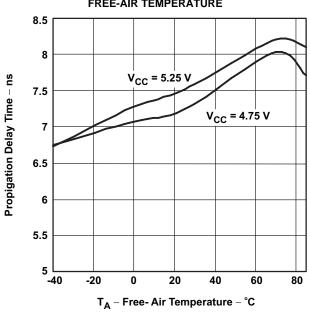


Figure 11.

# SUPPLY CURRENT (FOUR CHANNELS) vs

Figure 10.

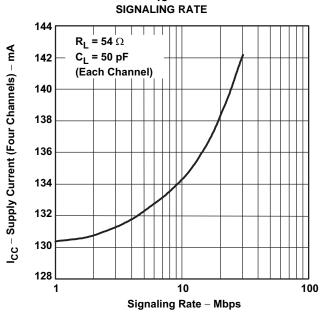
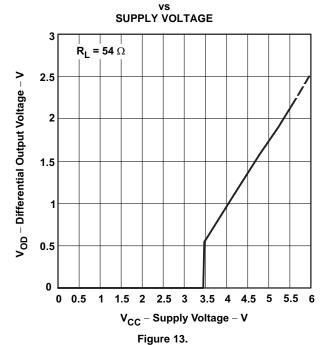


Figure 12.



# **TYPICAL CHARACTERISTICS (continued)**

#### **DIFFERENTIAL OUTPUT VOLTAGE**



#### EYE PATTERN, PSEUDORANDOM DATA AT+ 30 Mbps

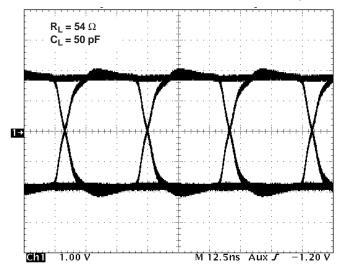


Figure 14.



#### **APPLICATION INFORMATION**

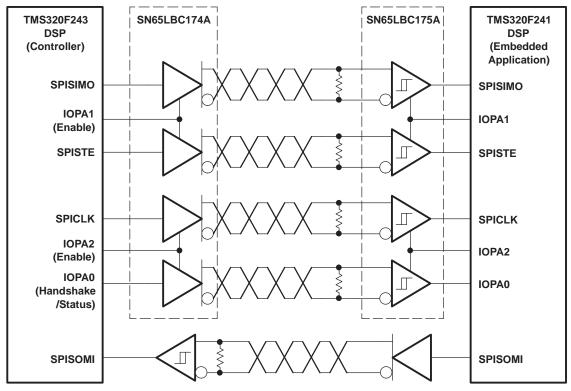
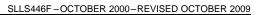


Figure 15. Typical Application Circuit, DSP-to-DSP Link via Serial Peripheral Interface
REVISION HISTORY

Cł	hanges from Original (October 2000) to Revision A	Page
•	Changed multiple items throught the data sheet.	1
CI	hanges from Revision A (February 2001) to Revision B	Page
•	Changed DW Package appearance	
CI	hanges from Revision B (June 2001) to Revision C	Page
•	Changed Features bullet From: Output ESD Protection Exceeds 13 kV To: Output ESD Protection: 11 kV	1
•	Changed Features bullet for Industry Standard From: Compatible With SN75174, MC3487, and DS96174 To: Compatible With SN75174, MC3487, DS96174, LTC487, and MAX3042	1
CI	hanges from Revision C (May 2003) to Revision D	Page
•	Changed the AVAILABLE OPTIONS table	2
•	Changed Electrostatic discharge-Human body model-Y, Z, and GND From: 13kV To: 11kV	3
•	Changed the DISSIPATION RATING TABLE	3





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C	hanges from Revision D (June 2008) to Revision E	Page
•	Changed Features bullet From: Output ESD Protection Exceeds 11 kV To: Output ESD Protection: 12 kV	1
•	Changed Electrostatic discharge-Human body model-Y, Z, and GND From: 11kV To: 12kV	3
•	From: A, G, G To: A, EN	4
С	hanges from Revision E (July 2008) to Revision F	Page
_	hanges from Revision E (July 2008) to Revision F  Changed FUNCTION TABLE header From: ENABLE G To: ENABLE EN	
•		2





10-Jun-2014

#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN65LBC174A16DW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174A16DWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174A16DWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174A16DWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174ADW	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174ADWG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174ADWR	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174ADWRG4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65LBC174A	Samples
SN65LBC174AN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 85	65LBC174A	Samples
SN75LBC174A16DW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	Samples
SN75LBC174A16DWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	Samples
SN75LBC174A16DWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	Samples
SN75LBC174ADW	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	Samples
SN75LBC174ADWG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	Samples
SN75LBC174ADWR	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	Samples
SN75LBC174ADWRG4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75LBC174A	Samples
SN75LBC174AN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	0 to 70	75LBC174A	Samples



# PACKAGE OPTION ADDENDUM

10-Jun-2014

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN75LBC174ANE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	0 to 70	75LBC174A	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF SN65LBC174A:



# **PACKAGE OPTION ADDENDUM**

10-Jun-2014

● Enhanced Product: SN65LBC174A-EP

NOTE: Qualified Version Definitions:

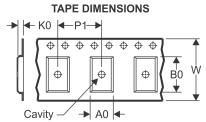
• Enhanced Product - Supports Defense, Aerospace and Medical Applications

PACKAGE MATERIALS INFORMATION

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# TAPE AND REEL INFORMATION





Α0	
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	_	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65LBC174A16DWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
SN65LBC174ADWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN75LBC174A16DWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
SN75LBC174ADWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1

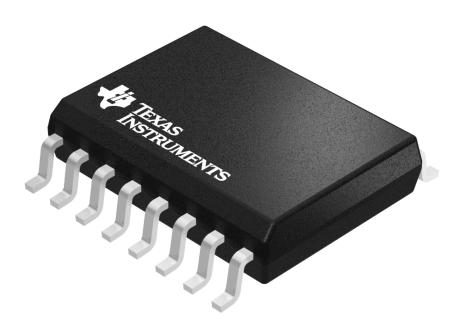
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\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65LBC174A16DWR	SOIC	DW	16	2000	367.0	367.0	38.0
SN65LBC174ADWR	SOIC	DW	20	2000	367.0	367.0	45.0
SN75LBC174A16DWR	SOIC	DW	16	2000	367.0	367.0	38.0
SN75LBC174ADWR	SOIC	DW	20	2000	367.0	367.0	45.0

SMALL OUTLINE INTEGRATED CIRCUIT



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4040000-2/H







#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing
- per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.
- 5. Reference JEDEC registration MS-013.





#### NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





#### NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# N (R-PDIP-T\*\*)

# PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.







#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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